

MOSFET – Power, Single N-Channel

60 V, 1.3 mΩ, 262 A

NVMJS1D4N06CL

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- LFPAK8 Package, Industry Standard
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25 °C unless otherwise noted)

| Parameter | | | Symbol | Value | Unit |
|--|--|-----------------------------------|-----------------|-------|------|
| Drain-to-Source Voltage | | | V_{DSS} | 60 | V |
| Gate-to-Source Voltage | | | V_{GS} | 20 | V |
| Continuous Drain | | T _C = 25 °C | I _D | 262 | Α |
| Current R _{θJC} (Notes 1, 3) | State | T _C = 100 °C | | 185 | |
| Power Dissipation | | T _C = 25 °C | P_{D} | 180 | W |
| R _{θJC} (Note 1) | | T _C = 100 °C | | 90 | |
| Continuous Drain Current R _{0JA} | Steady State | T _A = 25 °C | I _D | 39 | Α |
| (Notes 1, 2, 3) | State | T _A = 100 °C | | 28 | |
| Power Dissipation | | T _A = 25 °C | P_{D} | 4.0 | W |
| R _{θJA} (Notes 1 & 2) | | T _A = 100 °C | | 2.0 | |
| Pulsed Drain Current | $T_A = 25 {}^{\circ}\text{C}, t_p = 10 \mu\text{s}$ | | I _{DM} | 900 | Α |
| Operating Junction and Storage Temperature | | T _J , T _{stg} | –55 to + 175 | °C | |
| Source Current (Body Diode) | | | I _S | 150 | Α |
| Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 18.7 A) | | | E _{AS} | 1376 | mJ |
| Lead Temperature for Soldering Purposes (1/8" from case for 10 s) | | TL | 260 | °C | |

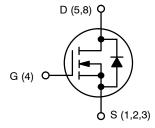
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|---|-------------------|-------|------|
| Junction-to-Case – Steady State | $R_{\theta JC}$ | 0.83 | °C/W |
| Junction-to-Ambient - Steady State (Note 2) | R _{0.IA} | 37.8 | 1 |

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

| V _{(BR)DSS} | R _{DS(ON)} MAX | I _D MAX |
|----------------------|-------------------------|--------------------|
| 60 V | 1.3 m Ω @ 10 V | 262 A |
| 00 V | 1.8 mΩ @ 4.5 V | 202 A |

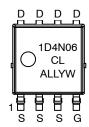


N-CHANNEL MOSFET

MARKING DIAGRAM



LFPAK8 CASE 760AA



1D4N06CL = Specific Device Code

A = Assembly Location

 LL
 = Wafer Lot

 Y
 = Year

 W
 = Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise specified)

| Parameter | Symbol | Test Condition | | Min | Тур | Max | Unit |
|--|-------------------------------------|--|-------------------------|-----|------|-----|-------|
| OFF CHARACTERISTICS | • | | | | | | |
| Drain-to-Source Breakdown Voltage | V _{(BR)DSS} | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ | | 60 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | V _{(BR)DSS} / | | | | 25 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{GS} = 0 V, | T _J = 25 °C | | | 10 | μΑ |
| | | $V_{DS} = 60 \text{ V}$ | T _J = 125 °C | | | 250 | 1 |
| Gate-to-Source Leakage Current | I _{GSS} | V _{DS} = 0 V, V _O | _{GS} = 20 V | | | 100 | nA |
| ON CHARACTERISTICS (Note 4) | | | | | | | |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_D = 280 \mu A$ | | 1.2 | | 2.0 | V |
| Threshold Temperature Coefficient | V _{GS(TH)} /T _J | | | | 5.3 | | mV/°C |
| Drain-to-Source On Resistance | R _{DS(on)} | V _{GS} = 4.5 V | I _D = 50 A | | 1.45 | 1.8 | mΩ |
| | | V _{GS} = 10 V | I _D = 50 A | | 1.07 | 1.3 | 1 |
| Forward Transconductance | 9FS | V _{DS} =15 V, | I _D = 50 A | | 244 | | S |
| CHARGES, CAPACITANCES & GATE F | RESISTANCE | | | | | • | - |
| Input Capacitance | C _{ISS} | V _{GS} = 0 V, f = 1 MHz, V _{DS} = 30 V | | | 7430 | | pF |
| Output Capacitance | C _{OSS} | | | | 3500 | | 1 |
| Reverse Transfer Capacitance | C _{RSS} | | | | 57 | | 1 |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 4.5 V, V _{DS} = 48 V; I _D = 50 A | | | 47 | | nC |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 10 V, V _{DS} = 48 V; I _D = 50 A | | | 103 | | 1 |
| Threshold Gate Charge | Q _{G(TH)} | V _{GS} = 4.5 V, V _{DS} = 48 V; I _D = 50 A | | | 10 | | 1 |
| Gate-to-Source Charge | Q_GS | | | | 17 | | 1 |
| Gate-to-Drain Charge | Q_GD | | | | 11 | | 1 |
| Plateau Voltage | V_{GP} | | | | 2.6 | | V |
| SWITCHING CHARACTERISTICS (Note | ÷ 5) | | | | • | | |
| Turn-On Delay Time | t _{d(ON)} | V_{GS} = 4.5 V, V_{DS} = 48 V, I_{D} = 50 A, R_{G} = 2.5 Ω | | | 29 | | ns |
| Rise Time | t _r | | | | 21 | | 1 |
| Turn-Off Delay Time | t _{d(OFF)} | | | | 52 | | 1 |
| Fall Time | t _f | | | | 19 | | 1 |
| DRAIN-SOURCE DIODE CHARACTER | STICS | | | | • | | |
| Forward Diode Voltage | V_{SD} | $V_{GS} = 0 V$, | T _J = 25 °C | | 0.78 | 1.2 | V |
| | | I _S = 50 A | T _J = 125 °C | | 0.66 | | |
| Reverse Recovery Time | t _{RR} | $V_{GS} = 0 \text{ V, } dI_{s}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$ | | | 86 | | ns |
| Charge Time | t _a | | | | 58 | | |
| Discharge Time | t _b | | | | 28 | | |
| Reverse Recovery Charge | Q _{RR} | 1 | | | 175 | | nC |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

5. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

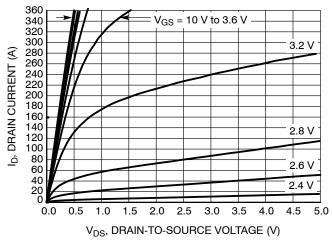


Figure 1. On-Region Characteristics

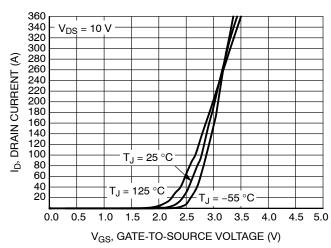


Figure 2. Transfer Characteristics

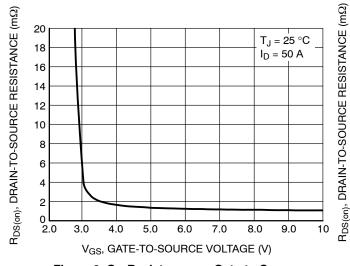


Figure 3. On-Resistance vs. Gate-to-Source Voltage

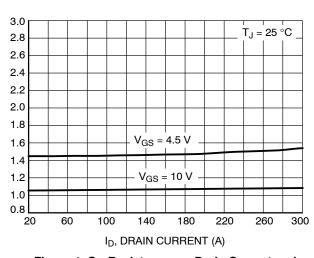


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

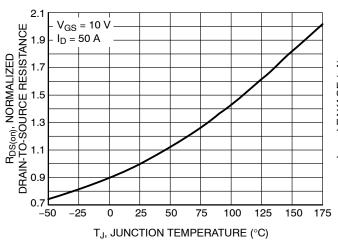


Figure 5. On-Resistance Variation with Temperature

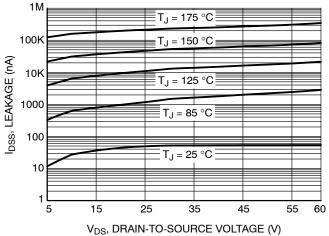


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

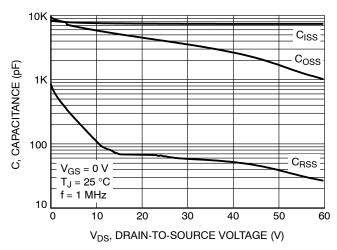


Figure 7. Capacitance Variation

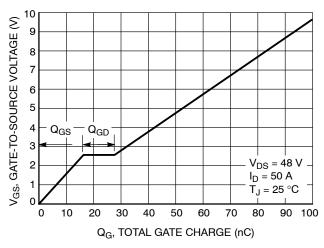


Figure 8. Gate-to-Source Voltage vs. Total Charge

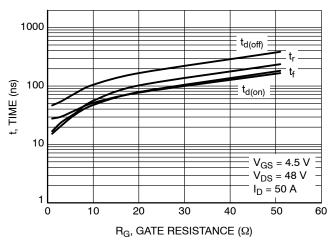


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

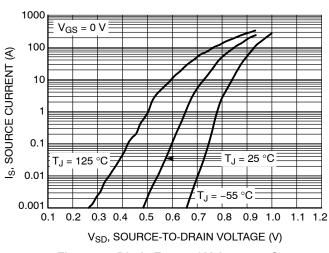


Figure 10. Diode Forward Voltage vs. Current

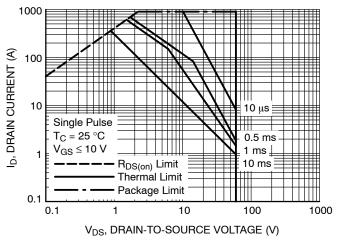


Figure 11. Maximum Rated Forward Biased Safe Operating Area

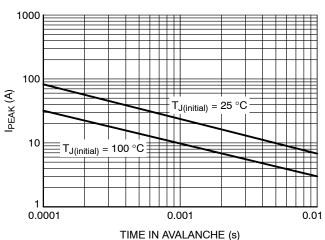


Figure 12. I_{PEAK} vs. Time in Avalanche

TYPICAL CHARACTERISTICS

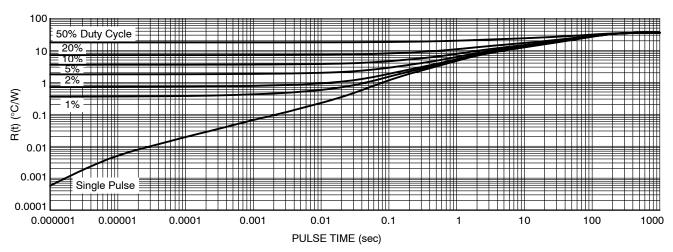


Figure 13. Thermal Characteristics

DEVICE ORDERING INFORMATION

| Device | Marking | Package | Shipping [†] |
|------------------|----------|---------------------|-----------------------|
| NVMJS1D4N06CLTWG | 1D4N06CL | LFPAK8 (Pb-Free) | 3000 / Tape & Reel |

[†] For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

REVISION HISTORY

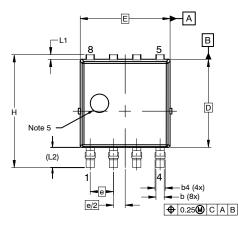
| Revision | Description of Changes | Date | |
|----------|---|------------|--|
| 0 | Initial document release. | 10/23/2019 | |
| 1 | Rebranded the document to onsemi format. | 10/25/2025 | |

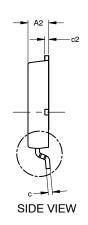




LFPAK8 4.90x4.80x1.12MM, **1.27P**CASE 760AA ISSUE D

DATE 22 APR 2024

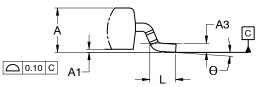


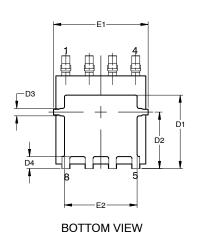


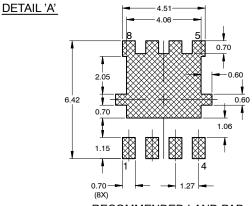
NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2018.
- CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- 4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. OPTIONAL MOLD FEATURE.









RECOMMENDED LAND PAD

*FOR ADDITIONAL INFORMATION ON OUR

MANUAL, SOLDERRM/D.

PB-FREE STRATEGY AND SOLDERING DETAILS.

PLEASE DOWNLOAD THE ONSEMI SOLDERING AND MOUNTING TECHNIQUES REFERENCE

MILLIMETERS MIN NOM DIM 1.10 1.20 1.30 Α A1 0.00 0.08 0.15 Α2 1.10 1.15 1.20 АЗ 0.25 BSC b 0.40 0.45 0.50 0.45 0.55 0.65 b4 0.19 0.22 0.25 С c2 0.19 0.22 0.25 4.70 4.80 4.90 D D1 3.80 4.00 4.20 2.98 D2 3.08 3.18 D3 0.30 0.40 0.50 D4 0.55 0.65 0.75 4.80 4.90 5.00 Ε E1 5.05 5.15 5.25 E2 3.91 3.96 4.01 1.27 BSC е 0.635 BSC e/2 Н 6.00 6.15 6.30 L 0.50 0.70 0.90 0.25 0.35 L1 0.15 L2 1.10 REF 4° θ

GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code

= Work Week

A = Assembly Location

WL = Wafer Lot Y = Year

W

*This information is generic. Please refer to device data sheet for actual part marking. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:

98AON82475G

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DESCRIPTION:

LFPAK8 4.90x4.80x1.12MM, 1.27P

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